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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	AVR
Core Size	8/16-Bit
Speed	32MHz
Connectivity	I ² C, IrDA, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, POR, PWM, WDT
Number of I/O	50
Program Memory Size	64KB (32K x 16)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 3.6V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-TQFP
Supplier Device Package	64-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/atxmega64c3-au

12. WDT – Watchdog Timer

12.1 Features

- Issues a device reset if the timer is not reset before its timeout period
- Asynchronous operation from dedicated oscillator
- 1kHz output of the 32kHz ultra low power oscillator
- 11 selectable timeout periods, from 8ms to 8s
- Two operation modes:
 - Normal mode
 - Window mode
- Configuration lock to prevent unwanted changes

12.2 Overview

The watchdog timer (WDT) is a system function for monitoring correct program operation. It makes it possible to recover from error situations such as runaway or deadlocked code. The WDT is a timer, configured to a predefined timeout period, and is constantly running when enabled. If the WDT is not reset within the timeout period, it will issue a microcontroller reset. The WDT is reset by executing the WDR (watchdog timer reset) instruction from the application code.

The window mode makes it possible to define a time slot or window inside the total timeout period during which WDT must be reset. If the WDT is reset outside this window, either too early or too late, a system reset will be issued. Compared to the normal mode, this can also catch situations where a code error causes constant WDR execution.

The WDT will run in active mode and all sleep modes, if enabled. It is asynchronous, runs from a CPU-independent clock source, and will continue to operate to issue a system reset even if the main clocks fail.

The configuration change protection mechanism ensures that the WDT settings cannot be changed by accident. For increased safety, a fuse for locking the WDT settings is also available.

17. AWeX – Advanced Waveform Extension

17.1 Features

- Waveform output with complementary output from each compare channel
- Four dead-time insertion (DTI) units
 - 8-bit resolution
 - Separate high and low side dead-time setting
 - Double buffered dead time
 - Optionally halts timer during dead-time insertion
- Pattern generation unit creating synchronised bit pattern across the port pins
 - Double buffered pattern generation
 - Optional distribution of one compare channel output across the port pins
- Event controlled fault protection for instant and predictable fault triggering

17.2 Overview

The advanced waveform extension (AWeX) provides extra functions to the timer/counter in waveform generation (WG) modes. It is primarily intended for use with different types of motor control and other power control applications. It enables low- and high side output with dead-time insertion and fault protection for disabling and shutting down external drivers. It can also generate a synchronized bit pattern across the port pins.

Each of the waveform generator outputs from the timer/counter 0 are split into a complimentary pair of outputs when any AWeX features are enabled. These output pairs go through a dead-time insertion (DTI) unit that generates the non-inverted low side (LS) and inverted high side (HS) of the WG output with dead-time insertion between LS and HS switching. The DTI output will override the normal port value according to the port override setting.

The pattern generation unit can be used to generate a synchronized bit pattern on the port it is connected to. In addition, the WG output from compare channel A can be distributed to and override all the port pins. When the pattern generator unit is enabled, the DTI unit is bypassed.

The fault protection unit is connected to the event system, enabling any event to trigger a fault condition that will disable the AWeX output. The event system ensures predictable and instant fault reaction, and gives flexibility in the selection of fault triggers.

The AWeX is available for TCC0. The notation of this is AWEXC.

20. USB – Universal Serial Bus Interface

20.1 Features

- One USB 2.0 full speed (12Mbps) and low speed (1.5Mbps) device compliant interface
- Integrated on-chip USB transceiver, no external components needed
- 16 endpoint addresses with full endpoint flexibility for up to 31 endpoints
 - One input endpoint per endpoint address
 - One output endpoint per endpoint address
- Endpoint address transfer type selectable to
 - Control transfers
 - Interrupt transfers
 - Bulk transfers
 - Isochronous transfers
- Configurable data payload size per endpoint, up to 1023 bytes
- Endpoint configuration and data buffers located in internal SRAM
 - Configurable location for endpoint configuration data
 - Configurable location for each endpoint's data buffer
- Built-in direct memory access (DMA) to internal SRAM for:
 - Endpoint configurations
 - Reading and writing endpoint data
- Ping-pong operation for higher throughput and double buffered operation
 - Input and output endpoint data buffers used in a single direction
 - CPU can update data buffer during transfer
- Multipacket transfer for reduced interrupt load and software intervention
 - Data payload exceeding maximum packet size is transferred in one continuous transfer
 - No interrupts or software interaction on packet transaction level
- Transaction complete FIFO for workflow management when using multiple endpoints
 - Tracks all completed transactions in a first-come, first-served work queue
- Clock selection independent of system clock source and selection
- Minimum 1.5MHz CPU clock required for low speed USB operation
- Minimum 12MHz CPU clock required for full speed operation
- Connection to event system
- On chip debug possibilities during USB transactions

20.2 Overview

The USB module is a USB 2.0 full speed (12Mbps) and low speed (1.5Mbps) device compliant interface.

The USB supports 16 endpoint addresses. All endpoint addresses have one input and one output endpoint, for a total of 31 configurable endpoints and one control endpoint. Each endpoint address is fully configurable and can be configured for any of the four transfer types; control, interrupt, bulk, or isochronous. The data payload size is also selectable, and it supports data payloads up to 1023 bytes.

No dedicated memory is allocated for or included in the USB module. Internal SRAM is used to keep the configuration for each endpoint address and the data buffer for each endpoint. The memory locations used for endpoint configurations and data buffers are fully configurable. The amount of memory allocated is fully dynamic, according to the number of endpoints in use and the configuration of these. The USB module has built-in direct memory access (DMA), and will read/write data from/to the SRAM when a USB transaction takes place.

To maximize throughput, an endpoint address can be configured for ping-pong operation. When done, the input and output endpoints are both used in the same direction. The CPU can then read/write one data buffer while the USB module writes/reads the others, and vice versa. This gives double buffered communication.

33.1.8 Bandgap and Internal 1.0V Reference Characteristics

Table 33-13. Bandgap and Internal 1.0V Reference Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Startup time	As reference for ADC	1 Clk _{PER} + 2.5μs			μs
		As input voltage to ADC and AC		1.5		
	Bandgap voltage			1.1		V
INT1V	Internal 1.00V reference	T= 85°C, after calibration	0.99	1.0	1.01	
	Variation over voltage and temperature	Calibrated at T= 85°C		1.0		%

33.1.9 Brownout Detection Characteristics

Table 33-14. Brownout Detection Characteristics⁽¹⁾

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V _{BOT}	BOD level 0 falling V _{CC}		1.40	1.60	1.70	V
	BOD level 1 falling V _{CC}			1.8		
	BOD level 2 falling V _{CC}			2.0		
	BOD level 3 falling V _{CC}			2.2		
	BOD level 4 falling V _{CC}			2.4		
	BOD level 5 falling V _{CC}			2.6		
	BOD level 6 falling V _{CC}			2.8		
	BOD level 7 falling V _{CC}			3.0		
t _{BOD}	Detection time	Continuous mode		0.4		μs
		Sampled mode		1000		
V _{HYST}	Hysteresis			1.0		%

Note: 1. BOD is calibrated at 85°C within BOD level 0 values, and BOD level 0 is the default level.

33.1.10 External Reset Characteristics

Table 33-15. External Reset Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
t _{EXT}	Minimum reset pulse width		1000	90		ns
V _{RST}	Reset threshold voltage	V _{CC} = 2.7 - 3.6V		0.45*V _{CC}		V
		V _{CC} = 1.6 - 2.7V		0.45*V _{CC}		
R _{RST}	Reset pin Pull-up Resistor			25		kΩ

33.3.14 SPI Characteristics

Figure 33-19. SPI Timing Requirements in Master Mode

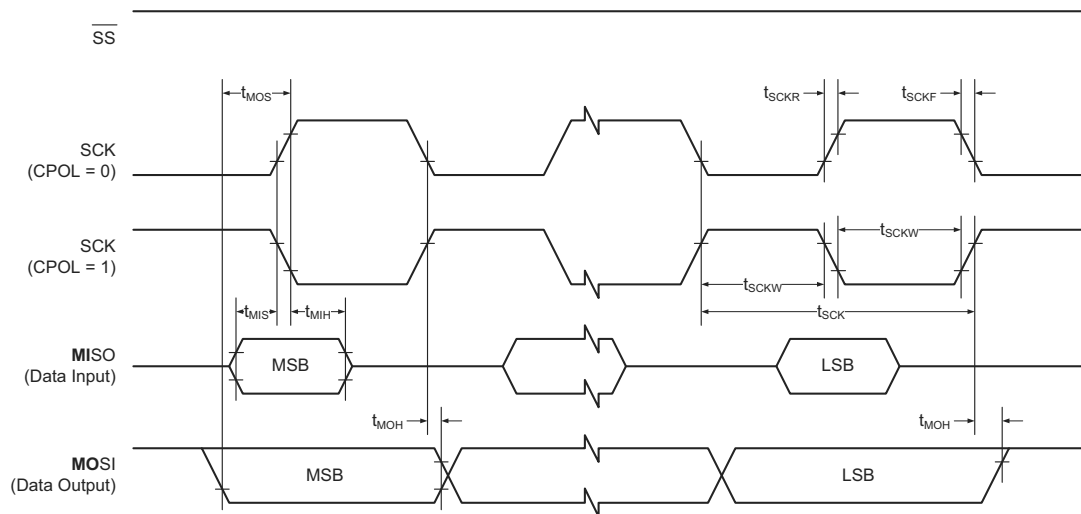
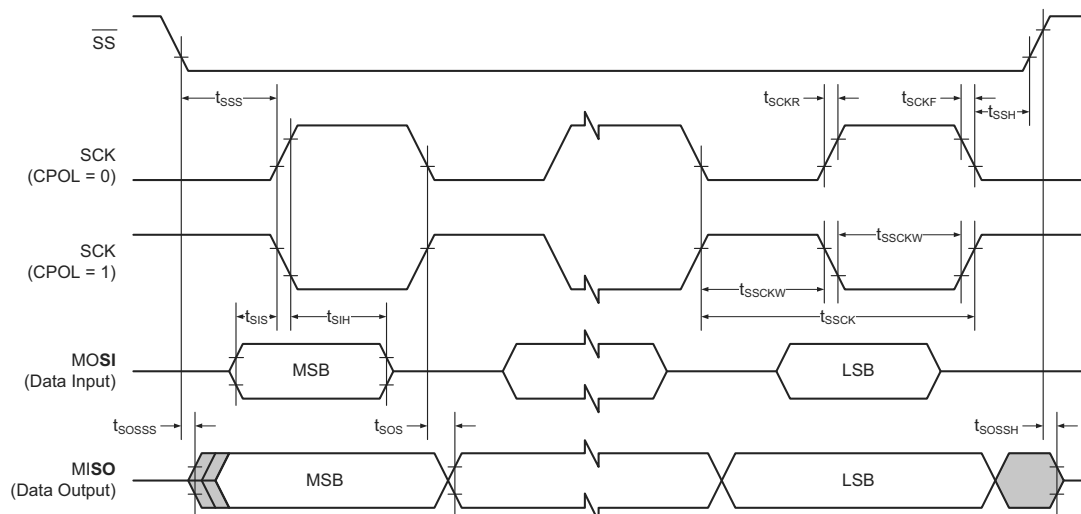


Figure 33-20. SPI Timing Requirements in Slave Mode



33.4.14 SPI Characteristics

Figure 33-26. SPI Timing Requirements in Master Mode

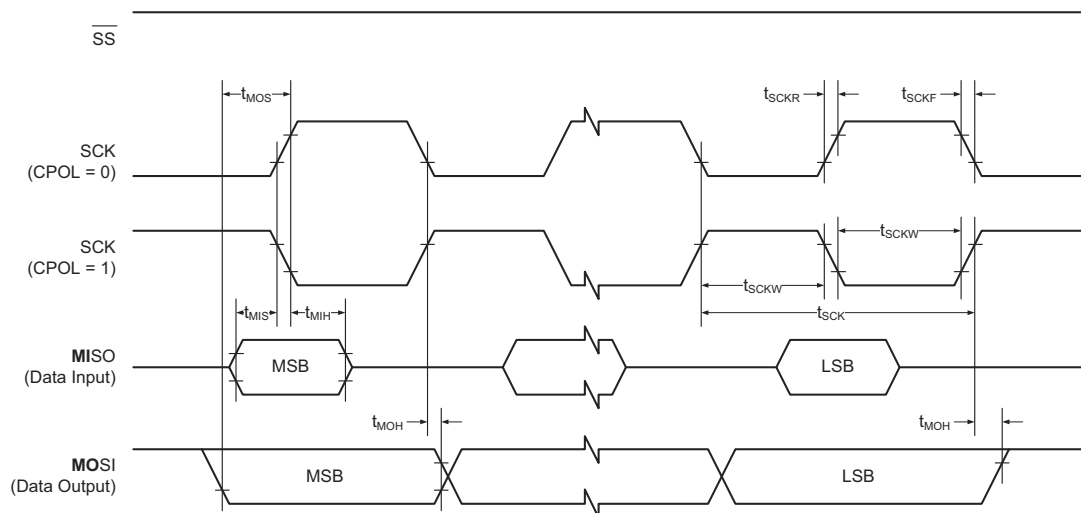
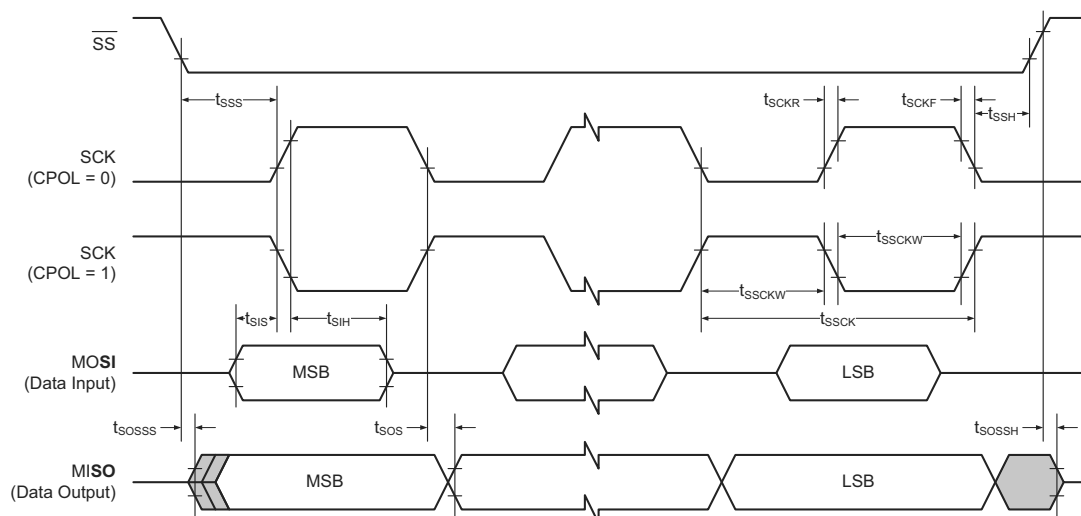


Figure 33-27. SPI Timing Requirements in Slave Mode



Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
R _Q	Negative impedance ⁽¹⁾	XOSCPWR=0, FRQRANGE=0	0.4MHz resonator, CL=100pF	44k		Ω
			1MHz crystal, CL=20pF	67k		
			2MHz crystal, CL=20pF	67k		
		XOSCPWR=0, FRQRANGE=1, CL=20pF	2MHz crystal	82k		
			8MHz crystal	1500		
			9MHz crystal	1500		
		XOSCPWR=0, FRQRANGE=2, CL=20pF	8MHz crystal	2700		
			9MHz crystal	2700		
			12MHz crystal	1000		
		XOSCPWR=0, FRQRANGE=3, CL=20pF	9MHz crystal	3600		
			12MHz crystal	1300		
			16MHz crystal	590		
		XOSCPWR=1, FRQRANGE=0, CL=20pF	9MHz crystal	390		
			12MHz crystal	50		
			16MHz crystal	10		
		XOSCPWR=1, FRQRANGE=1, CL=20pF	9MHz crystal	1500		
			12MHz crystal	650		
			16MHz crystal	270		
		XOSCPWR=1, FRQRANGE=2, CL=20pF	12MHz crystal	1000		
			16MHz crystal	440		
		XOSCPWR=1, FRQRANGE=3, CL=20pF	12MHz crystal	1300		
			16MHz crystal	590		
	ESR	SF = safety factor			min(R _Q)/SF	kΩ
	Startup time	XOSCPWR=0, FRQRANGE=0	0.4MHz resonator, CL=100pF	1.0		ms
		XOSCPWR=0, FRQRANGE=1	2MHz crystal, CL=20pF	2.6		
		XOSCPWR=0, FRQRANGE=2	8MHz crystal, CL=20pF	0.8		
		XOSCPWR=0, FRQRANGE=3	12MHz crystal, CL=20pF	1.0		
		XOSCPWR=1, FRQRANGE=3	16MHz crystal, CL=20pF	1.4		

Figure 34-3. Active Mode Supply Current vs. V_{CC}

$f_{SYS} = 32.768\text{kHz}$ internal oscillator

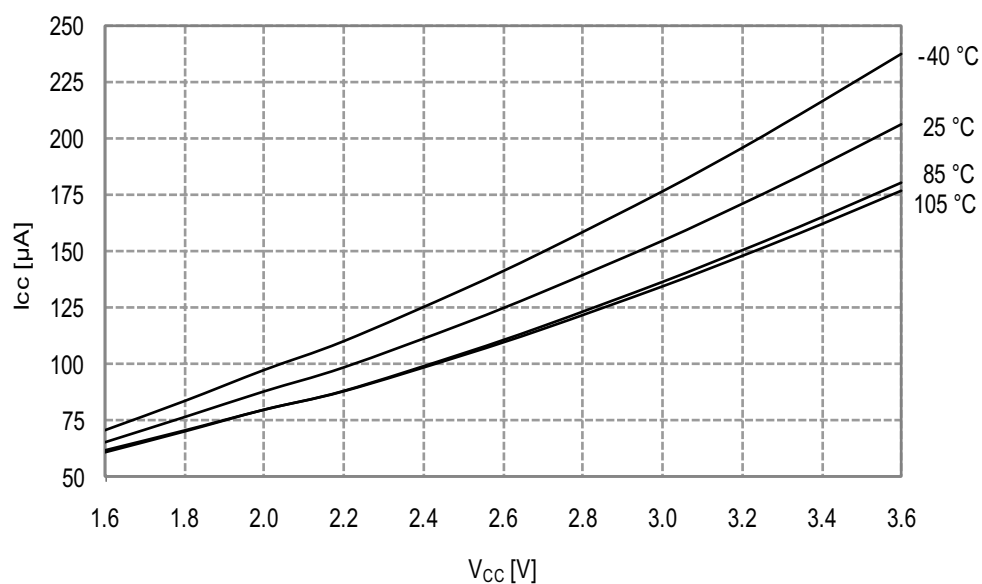


Figure 34-4. Active Mode Supply Current vs. V_{CC}

$f_{SYS} = 1\text{MHz}$ external clock

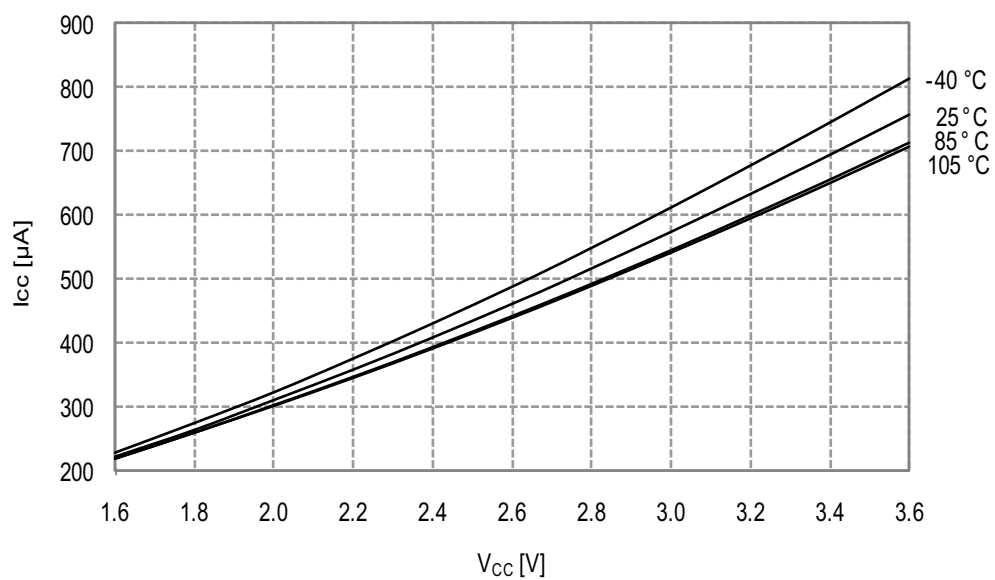


Figure 34-74.Active Mode Supply Current vs. V_{CC}

$f_{SYS} = 32.768kHz$ internal oscillator

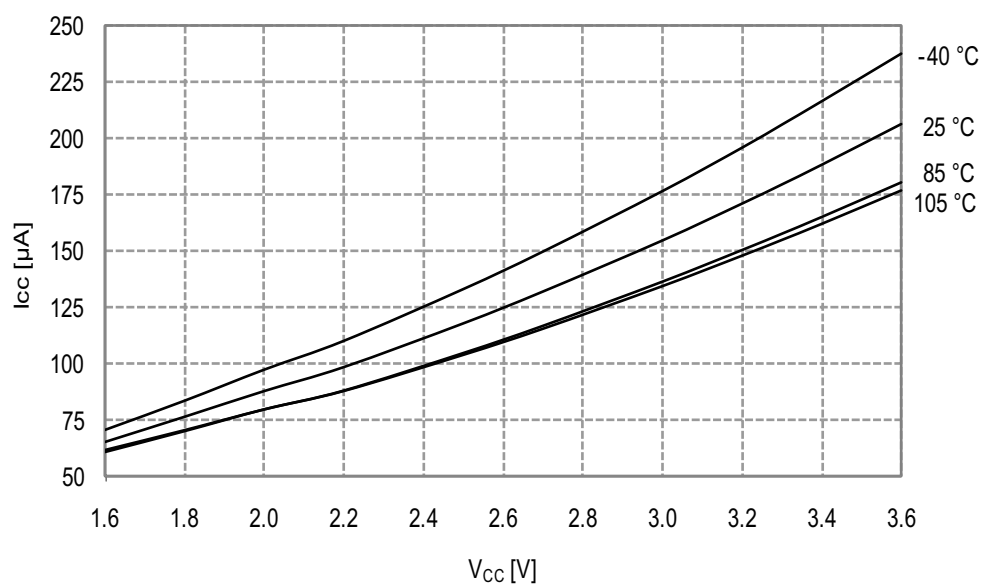


Figure 34-75.Active Mode Supply Current vs. V_{CC}

$f_{SYS} = 1MHz$ external clock

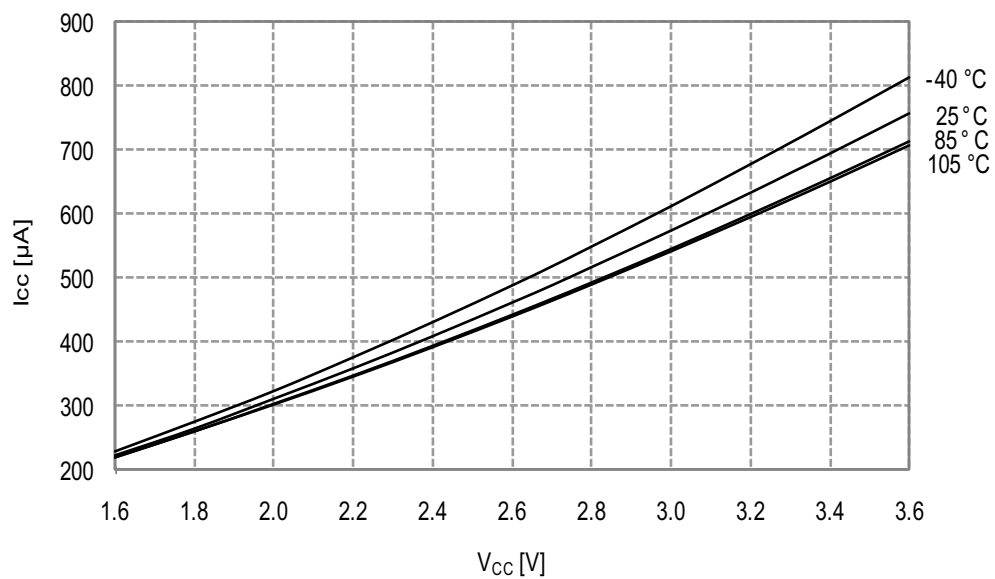


Figure 34-108. Gain Error vs. V_{REF}

$T = 25^{\circ}\text{C}$, $V_{CC} = 3.6\text{V}$, ADC sample rate = 300ksps

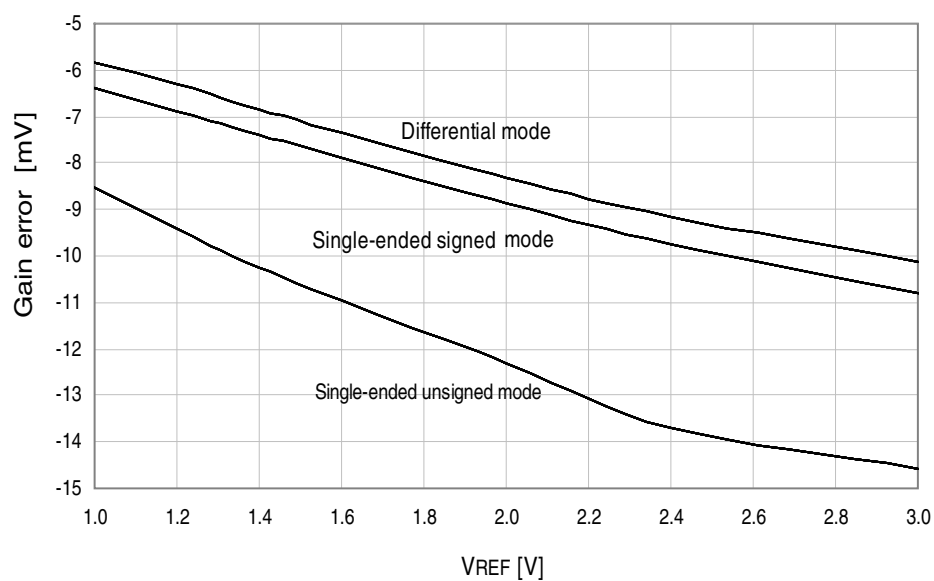


Figure 34-109. Gain Error vs. V_{CC}

$T = 25^{\circ}\text{C}$, $V_{REF} = \text{external } 1.0\text{V}$, ADC sample rate = 300ksps

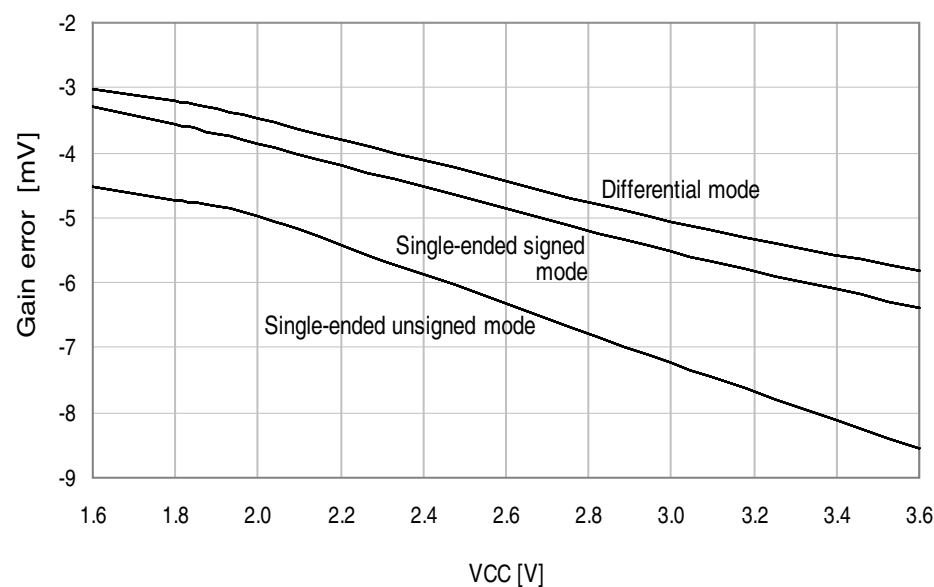
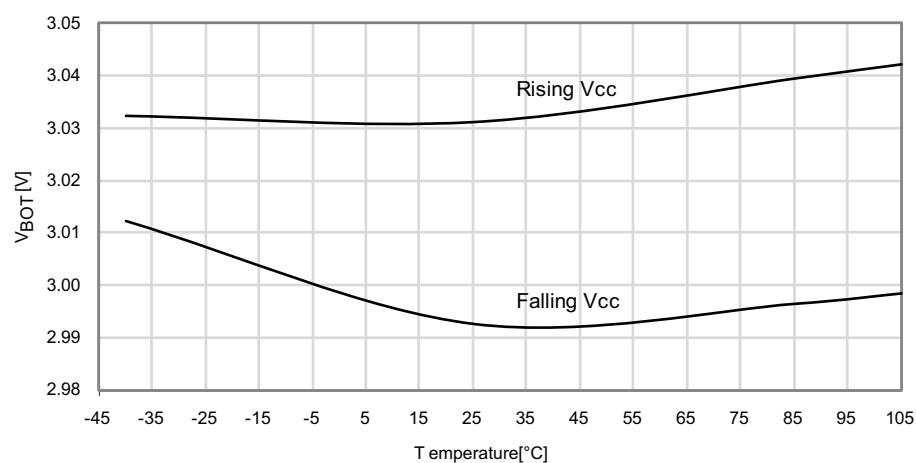


Figure 34-189. BOD Thresholds vs. Temperature

BOD level = 3.0V



34.3.7 External Reset Characteristics

Figure 34-190. Minimum Reset Pin Pulse Width vs. V_{CC}

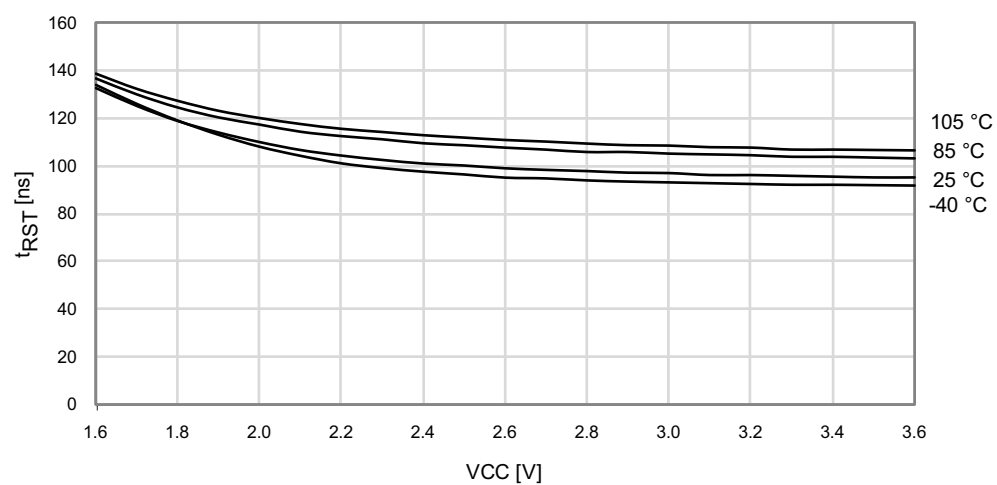
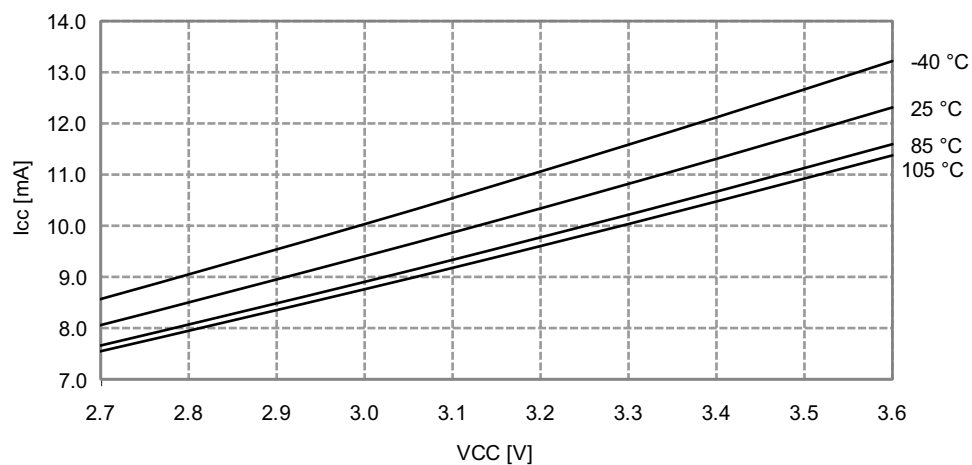


Figure 34-219. Active Mode Supply Current vs. V_{CC}

$f_{SYS} = 32\text{MHz}$ internal oscillator



34.4.1.2 Idle Mode Supply Current

Figure 34-220. Idle Mode Supply Current vs. Frequency

$f_{SYS} = 0 - 1\text{MHz}$ external clock, $T = 25^{\circ}\text{C}$

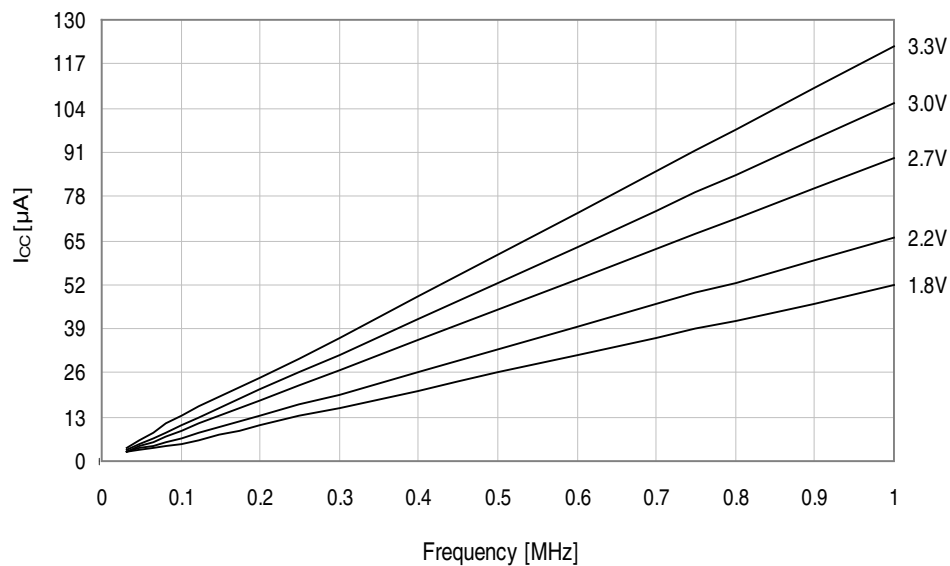


Figure 34-247. DNL Error vs. Input Code

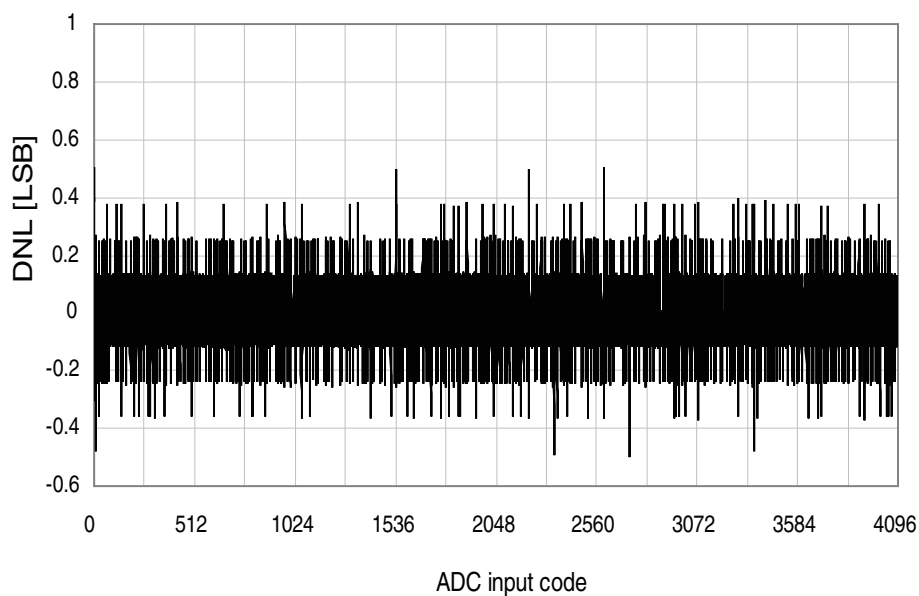


Figure 34-248. Gain Error vs. V_{REF}
 $T = 25^{\circ}\text{C}$, $V_{CC} = 3.6\text{V}$, ADC sample rate = 300ksps

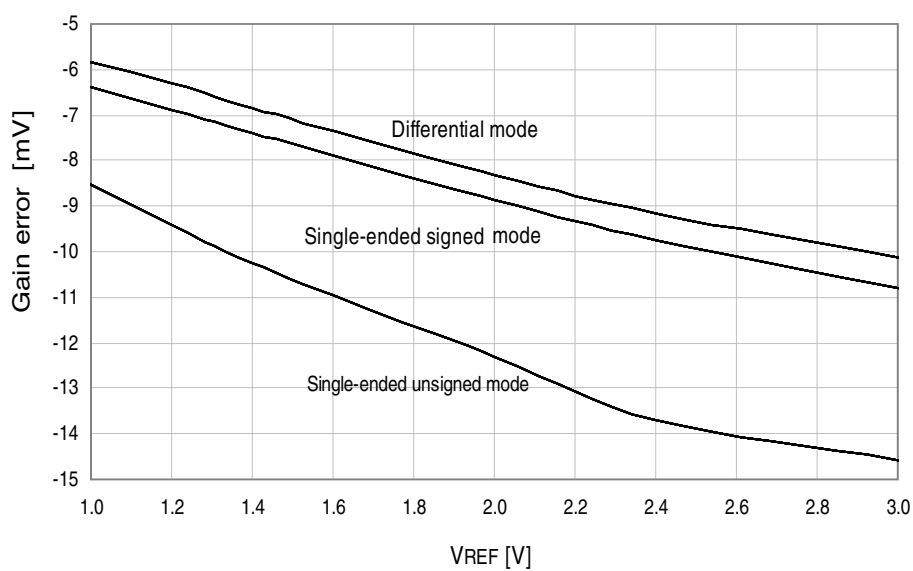
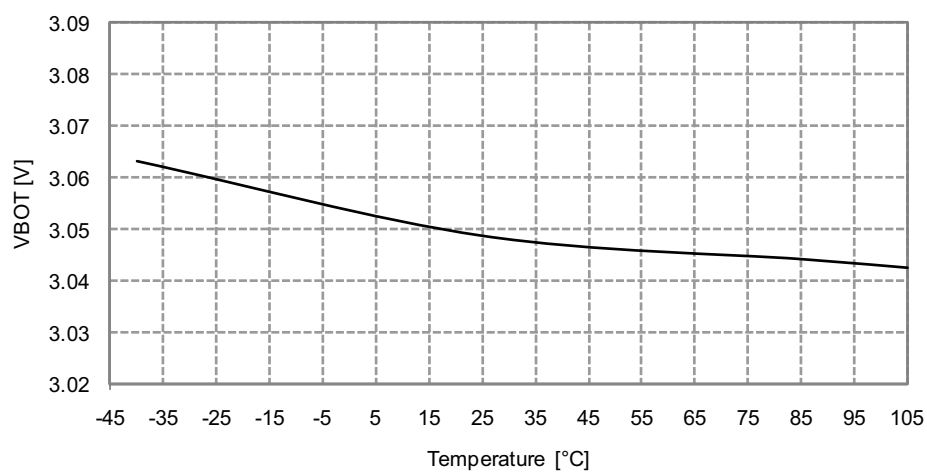


Figure 34-259. BOD Thresholds vs. Temperature

BOD level = 3.0V



34.4.7 External Reset Characteristics

Figure 34-260. Minimum Reset Pin Pulse Width vs. V_{CC}

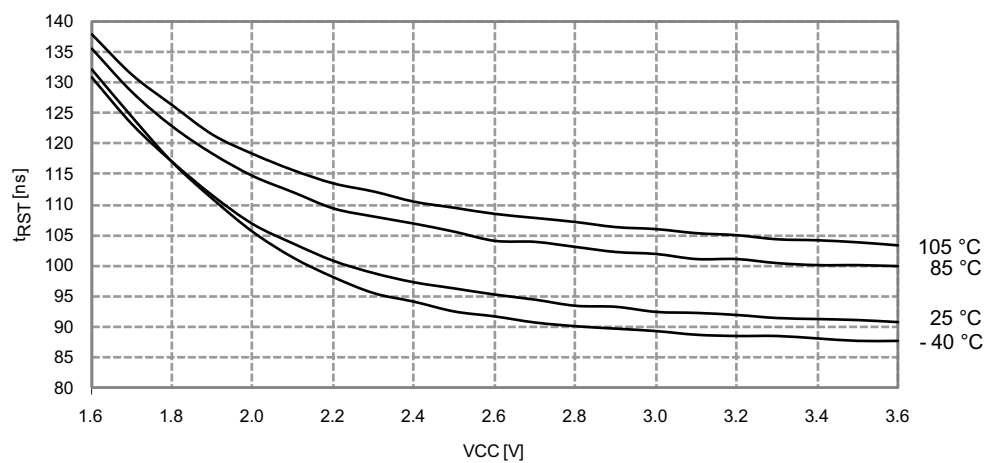


Figure 34-301. I/O Pin Pull-up Resistor Current vs. Input Voltage

$V_{CC} = 3.0V$

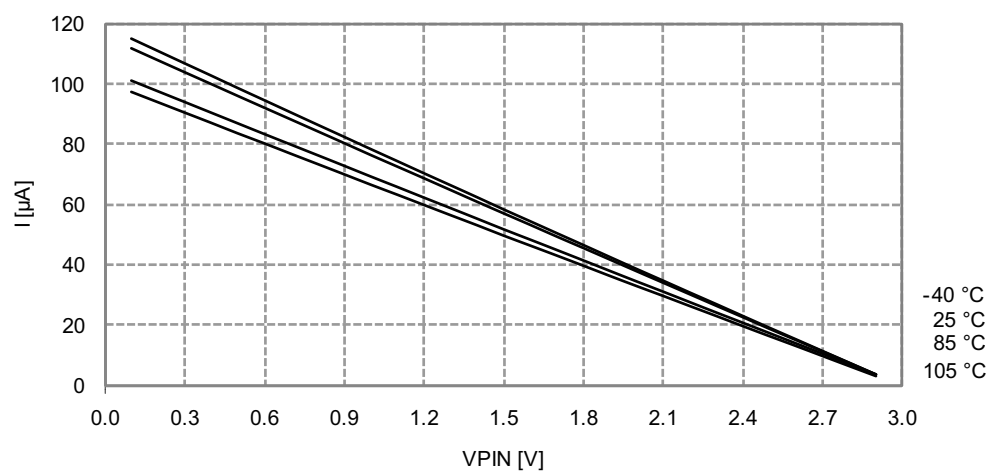


Figure 34-302. I/O Pin Pull-up Resistor Current vs. Input Voltage

$V_{CC} = 3.3V$

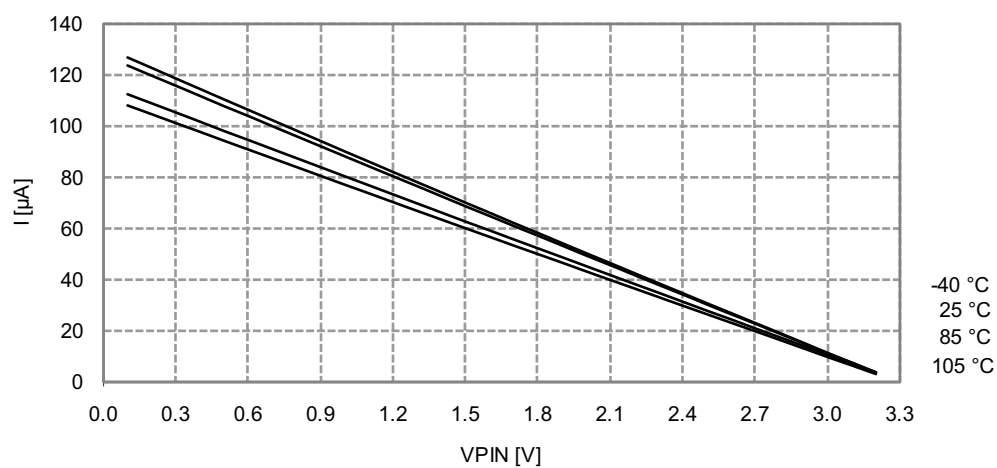
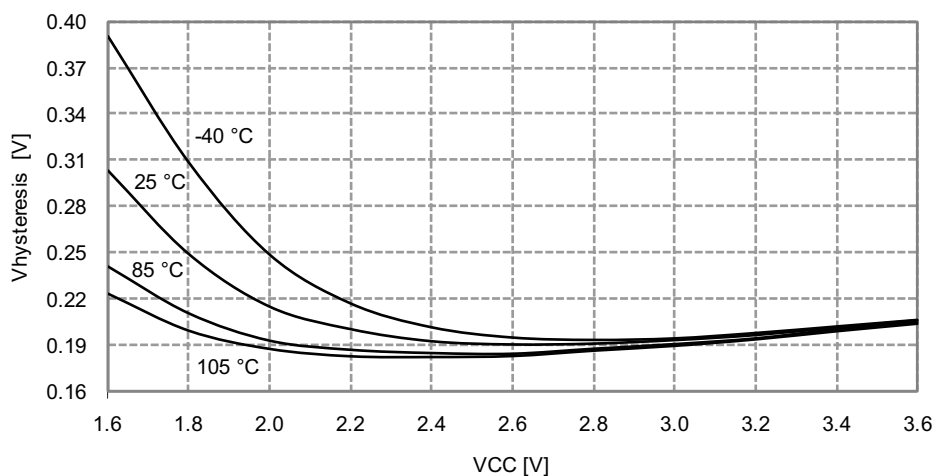


Figure 34-311. I/O Pin Input Hysteresis vs. V_{CC}



34.5.3 ADC Characteristics

Figure 34-312. INL Error vs. External V_{REF}
 $T = 25^{\circ}\text{C}$, $V_{CC} = 3.6\text{V}$, external reference

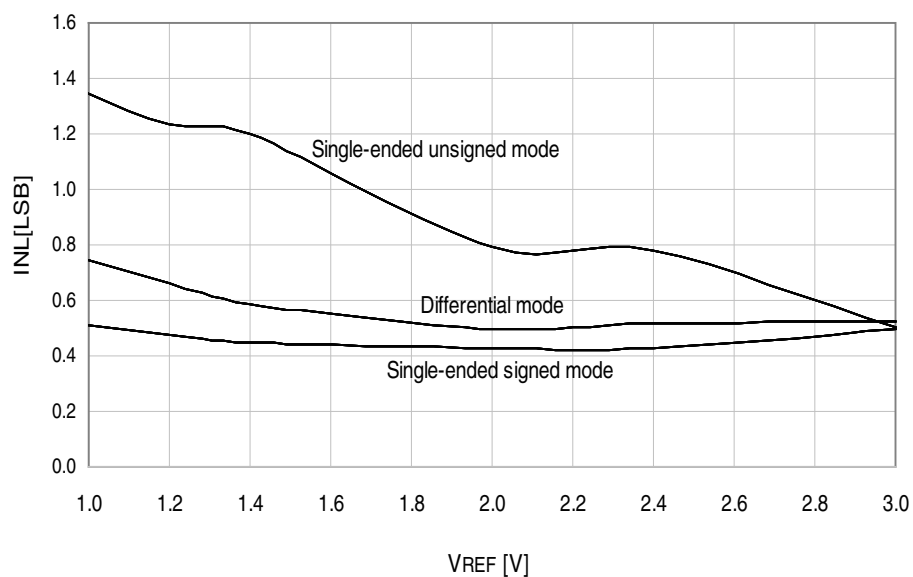


Figure 34-313. INL Error vs. Sample Rate

$T = 25^{\circ}\text{C}$, $V_{CC} = 3.6\text{V}$, $V_{REF} = 3.0\text{V external}$

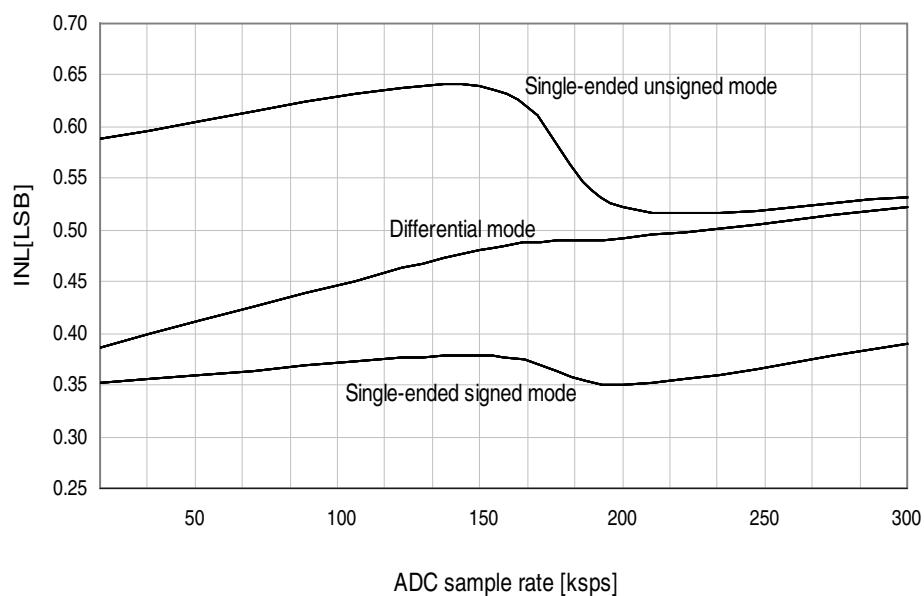


Figure 34-314. INL Error vs. Input Code

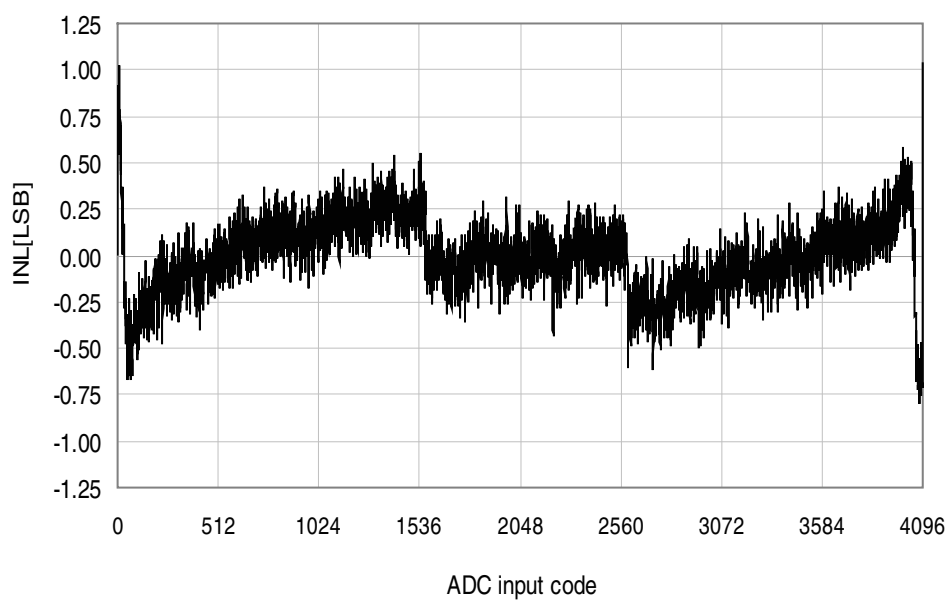


Figure 34-317. DNL Error vs. Input Code

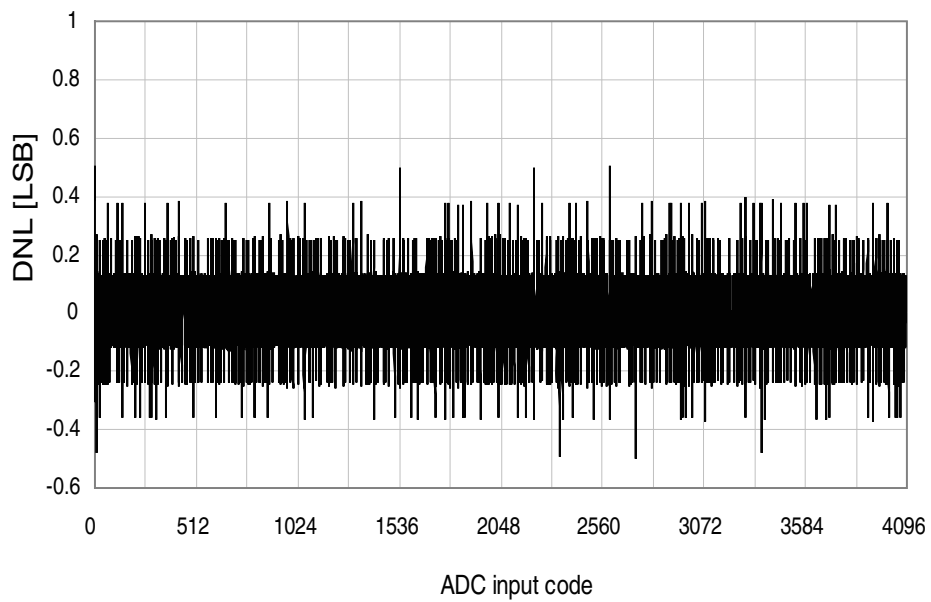


Figure 34-318. Gain Error vs. V_{REF}

$T = 25^{\circ}\text{C}$, $V_{CC} = 3.6\text{V}$, ADC sample rate = 300ksps

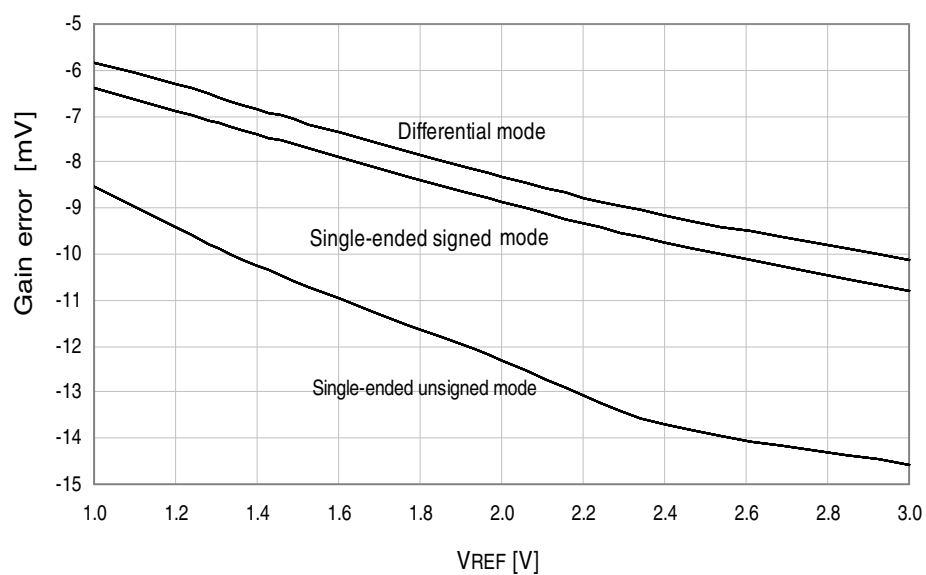


Figure 34-319. Gain Error vs. V_{CC}

$T = 25^{\circ}\text{C}$, $V_{REF} = \text{external } 1.0\text{V}$, ADC sample rate = 300ksps

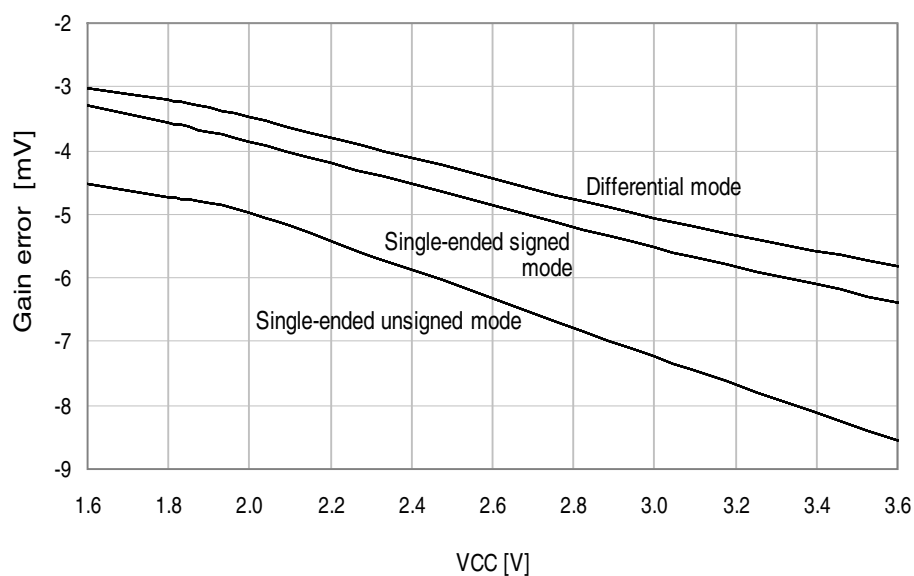


Figure 34-320. Offset Error vs. V_{REF}

$T = 25^{\circ}\text{C}$, $V_{CC} = 3.6\text{V}$, ADC sample rate = 300ksps

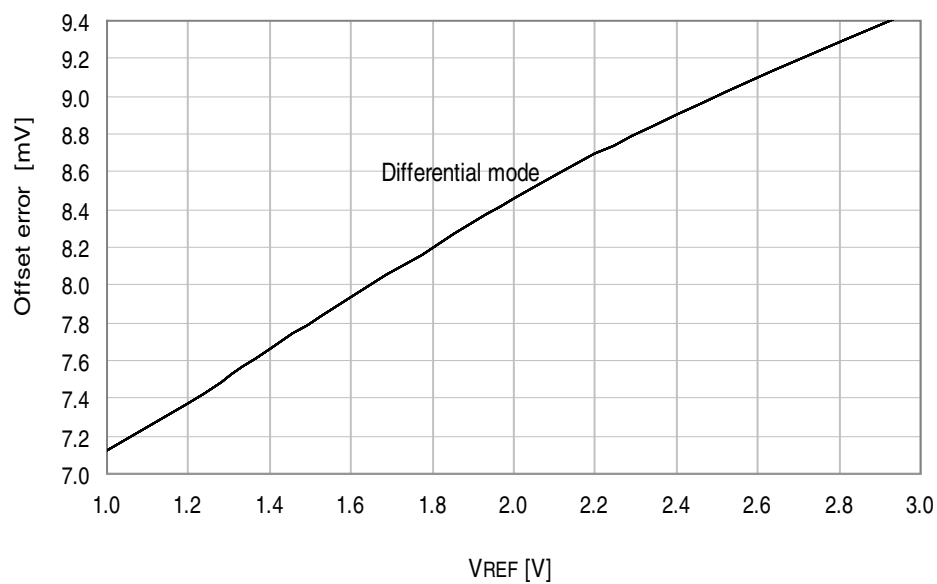
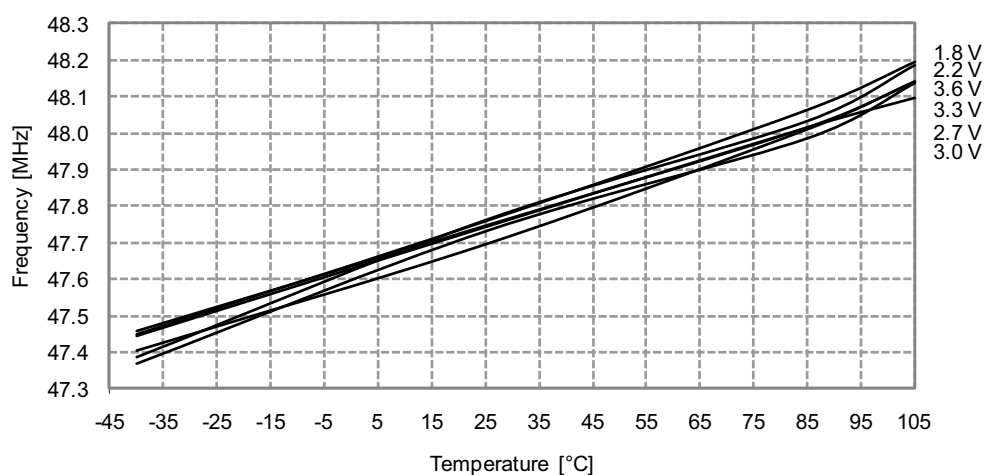


Figure 34-349. 48MHz Internal Oscillator Frequency vs. Temperature
DFLL enabled, from the 32.768kHz internal oscillator



34.5.9 Two-Wire Interface Characteristics

Figure 34-350. SDA Hold Time vs. Temperature

